

Structure, magnetism and excitations in some Mn-based magnetocaloric effect compounds

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Schriften des Forschungszentrums Jülich
Reihe Schlüsseltechnologien / Key Technologies

Band / Volume 62

ISSN 1866-1807

ISBN 978-3-89336-874-7

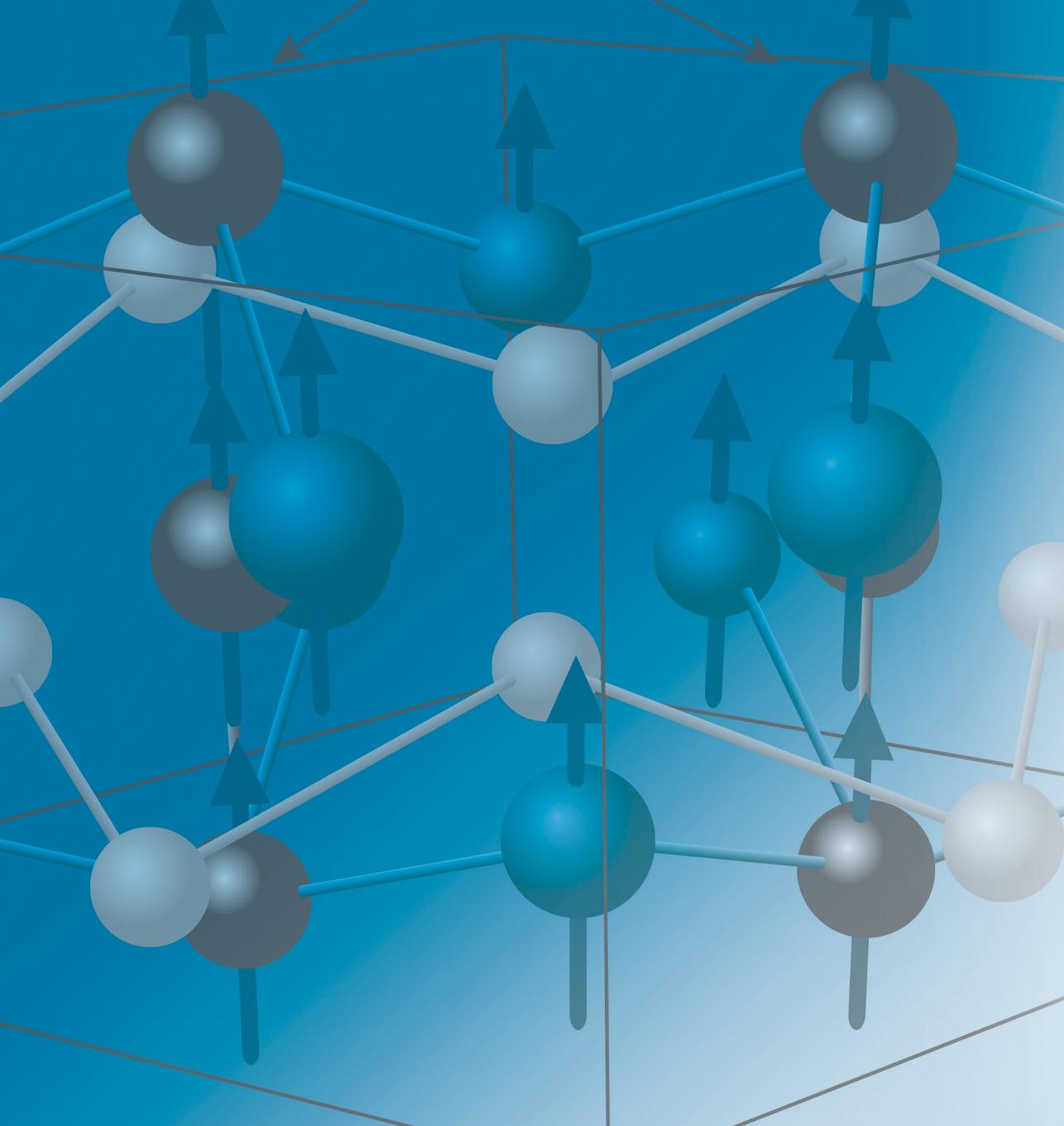
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Schlüsseltechnologien / Key Technologies
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ISBN 978-3-89336-874-7